


<b>Search Notes</b>  	<b>Application/Control No.</b>  10509367	<b>Applicant(s)/Patent Under Reexamination</b>  KIM ET AL.
	<b>Examiner</b>  TAN X DINH	<b>Art Unit</b>  2627

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (see search history printout)	9/04/08	T.D

INTERFERENCE SEARCH			
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